



# Am29821/823/825

## High Performance Bus Interface Registers

### DISTINCTIVE CHARACTERISTICS

- High-speed parallel registers with positive edge-triggered D-type flip-flops
  - Noninverting CP-Y  $t_{PD} = 7.5$  ns typ
  - Inverting CP-Y  $t_{PD} = 7.5$  ns typ
- Buffered common Clock Enable ( $\overline{EN}$ )
- Buffered common asynchronous Clear input (CLR)
- Three-state outputs glitch free during power-up and down
- Outputs have Schottky clamp to ground
- 48 mA Commercial  $I_{OL}$
- Low input/output capacitance
  - 6 pF inputs (typical)
  - 8 pF outputs (typical)
- Metastable "Hardened" Registers
- $I_{OH}$  specified at 2.0 V and 2.4 V
- 24-pin 0.3" space saving package
- IMOXTM high performance Implanted Oxide isolated process

### GENERAL DESCRIPTION

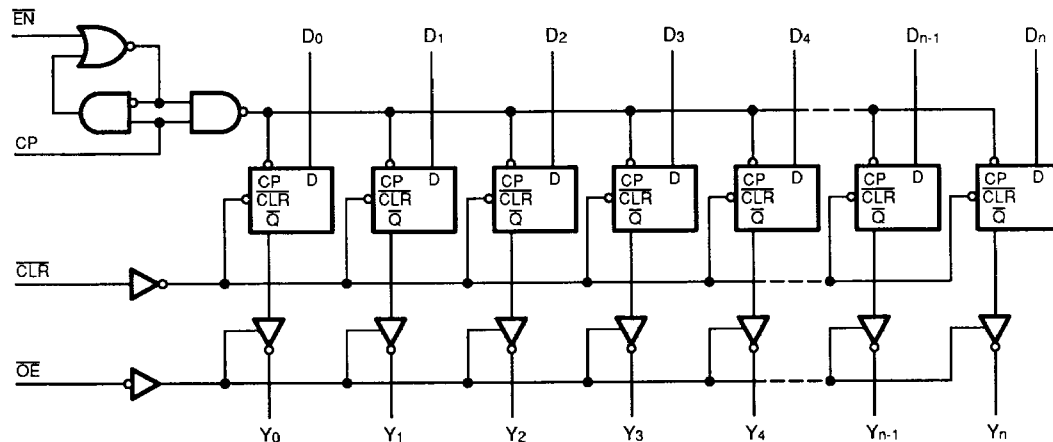
The Am29821/823/825 bus interface registers are designed to eliminate the extra packages required to buffer existing registers and provide extra data width for wider address/data paths or buses carrying parity. The Am29821 is a buffered, 10-bit wide version of the popular '374/'534 functions. The Am29823 is a 9-bit wide buffered register with Clock Enable ( $\overline{EN}$ ) and Clear (CLR) – ideal for parity bus interfacing in high performance microprogrammed systems. The Am29825 is an 8-bit buffered register with all the '823 controls plus mul-

ti-ple enables ( $\overline{OE}_1$ ,  $\overline{OE}_2$ ,  $\overline{OE}_3$ ) to allow multiuser control of the interface, e.g.,  $\overline{CS}$ , DMA, and  $RD/\overline{WR}$ . It is ideal for use as an output port requiring high  $I_{OL}/I_{OH}$ .

All of the Am29800 high performance interface family are designed for high capacitance load drive capability while providing low capacitance bus loading at both inputs and outputs. All inputs are Schottky diode inputs, and all outputs are designed for low capacitance bus loading in the high impedance state.

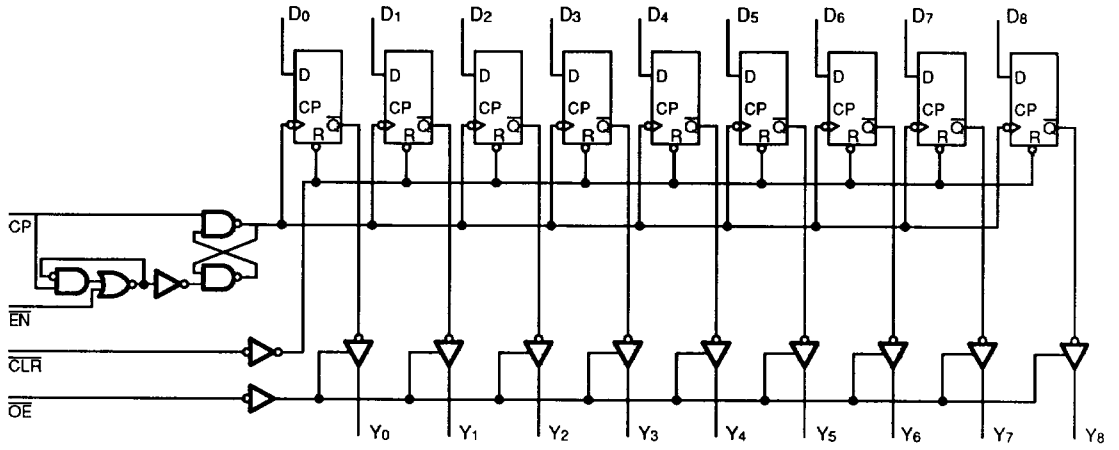
### BLOCK DIAGRAMS

#### Am29821



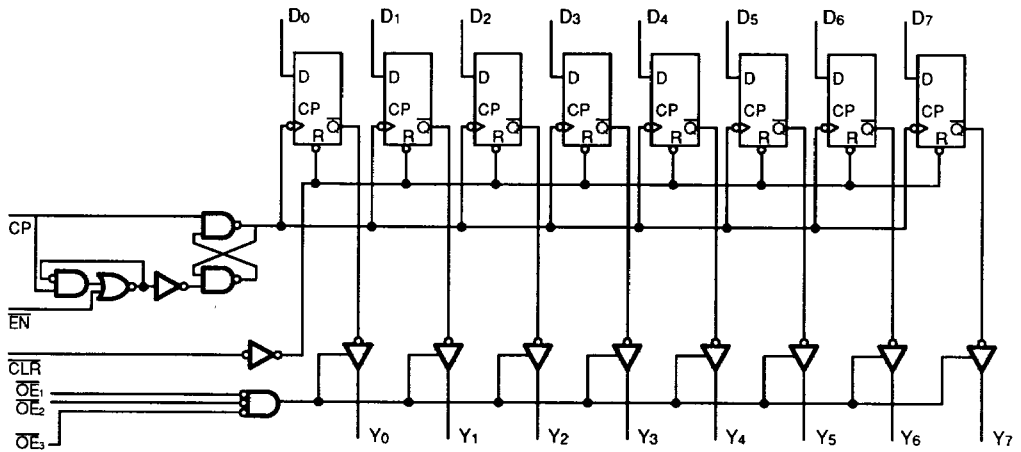
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**BLOCK DIAGRAMS (Continued)**  
**Am29823**



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**Am29825**

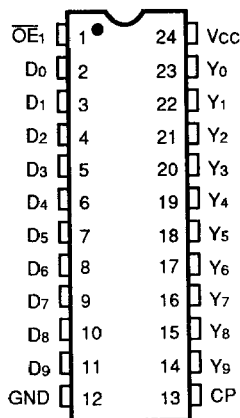


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**CONNECTION DIAGRAMS**  
Top View

**Am29821**

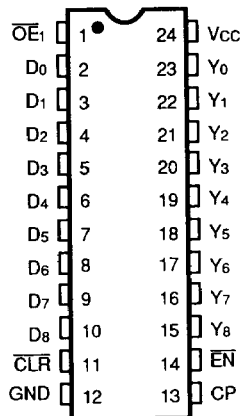
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**Am29823**

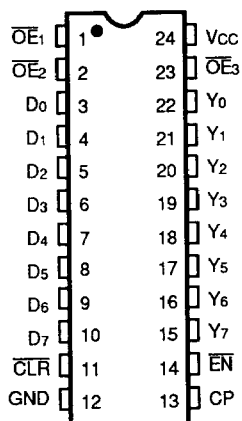
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**Am29825**

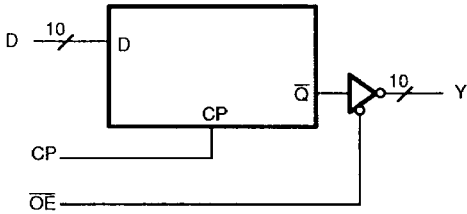
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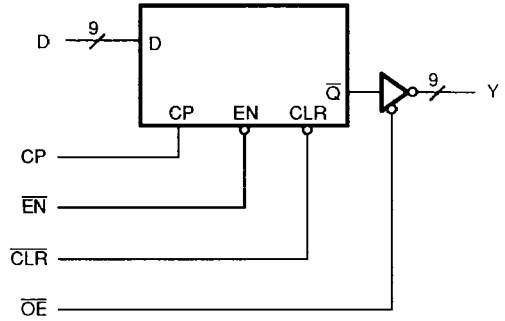
LOGIC SYMBOLS

**Am29821  
10-Bit Register**



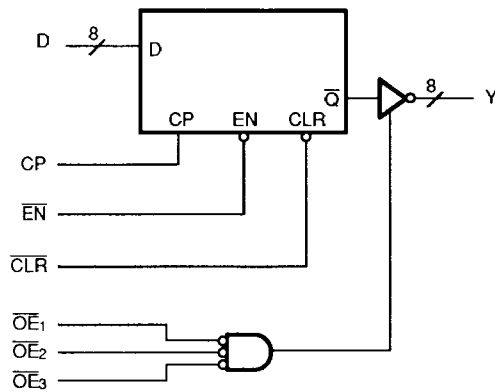
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**Am29823  
9-Bit Register**



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**Am29825  
8-Bit Register**



01420-009A

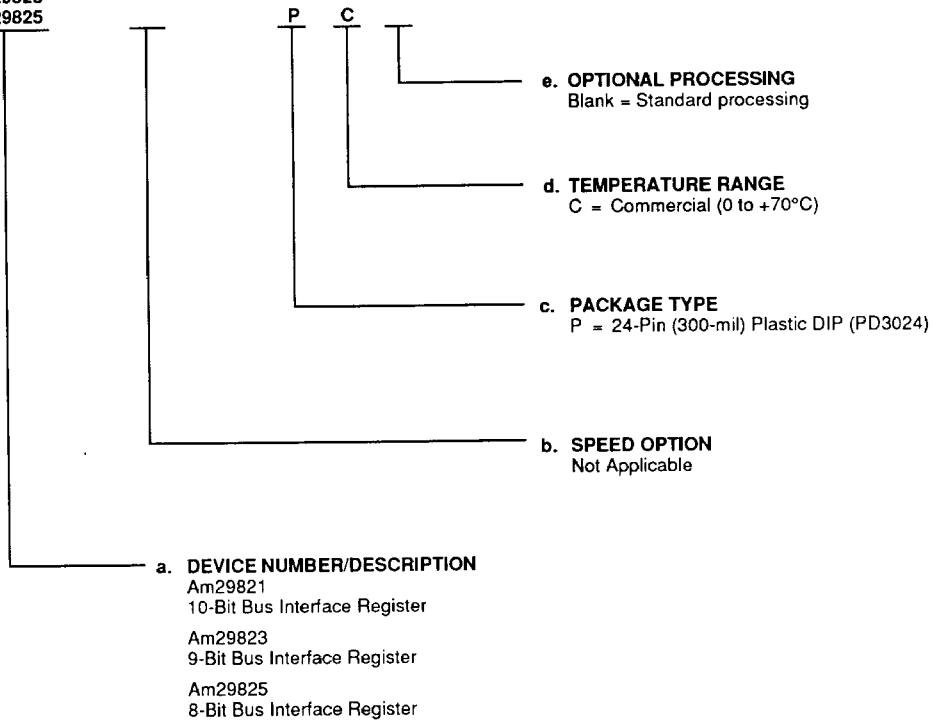
## ORDERING INFORMATION

### Standard Products

AMD standard products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of:

- a. Device Number
- b. Speed Option (if applicable)
- c. Package Type
- d. Temperature Range
- e. Optional Processing

AM29821  
AM29823  
AM29825



Valid Combinations	
AM29821	PC
AM29823	
AM29825	

#### Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations or to check on newly released combinations, and to obtain additional data on AMD's standard military grade products.

## PIN DESCRIPTION

### $D_i$

The D flip-flop data inputs.

### $\overline{CLR}$

For both inverting and noninverting register, when the clear input is LOW and  $\overline{OE}$  is LOW, the  $Q_i$  outputs are LOW. When the clear input is HIGH, data can be entered into the register.

### CP

Clock Pulse for the Register; enters data into the register on the LOW-to-HIGH transition.

### $Y_i$

The register three-state outputs.

### Note:

1. The Am29823 and Am29825 registers achieve short throughput delay and setup time and reduced power consumption by means of a clock gating and latching circuit. This circuit is sensitive to very short (<3 ns) HIGH-to-LOW-to-HIGH going spikes on  $\overline{EN}$  while CP is HIGH. The designer should be aware of this and avoid the use of decoders or other potentially glitching devices in the  $\overline{EN}$  logic.

### $\overline{EN}$

Clock Enable. When the clock enable is LOW, data on the  $D_i$  input is transferred to the  $Q_i$  output on the LOW-to-HIGH clock transition. When the clock enable is HIGH, the  $Q_i$  outputs do not change state, regardless of the data or clock input transitions. (Note 1.)

### $\overline{OE}$

Output Control. When the  $\overline{OE}$  input is HIGH, the  $Y_i$  outputs are in the high impedance state. When the  $\overline{OE}$  input is LOW, the TRUE register data is present at the  $Y_i$  outputs.

## FUNCTION TABLE

Inputs					Internal	Outputs	Function
$\overline{OE}$	$\overline{CLR}$	$\overline{EN}$	$D_i$	CP	$Q_i$	$Y_i$	
H	X	L	L	↑	L	Z	Hi-Z
H	X	L	H	↑	H	Z	
H	L	X	X	X	L	Z	Clear
L	L	X	X	X	L	L	
H	H	H	X	X	NC	Z	Hold
L	H	H	X	X	NC	NC	
H	H	L	L	↑	L	Z	Load
H	H	L	H	↑	H	Z	
L	H	L	L	↑	L	L	
L	H	L	H	↑	H	H	

H = HIGH

L = LOW

X = Don't Care

NC = No Change

↑ = LOW-to-HIGH Transition

Z = High Impedance

## ABSOLUTE MAXIMUM RATINGS

Storage Temperature	-65°C to +150°C
Ambient Temperature with Power Applied	-55°C to +125°C
Supply Voltage to Ground Potential Continuous	-0.5 V to +7.0 V
DC Voltage Applied to Outputs for High Output State	-0.5 V to +5.5 V
DC Input Voltage	-0.5 V to +5.5 V
DC Output Current, Into Outputs	100 mA
DC Input Current	-30 mA to +5.0 mA

## OPERATING RANGES

### Commercial (C) Devices

Ambient Temperature, (T <sub>A</sub> )	0°C to +70°C
Supply Voltage, (V <sub>CC</sub> )	5.0 V ± 10% 4.5 V to 5.5 V

Operating ranges define those limits between which the functionality of the device is guaranteed.

Stresses above those listed under Absolute Maximum Ratings may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

## DC CHARACTERISTICS over operating ranges unless otherwise specified

Parameter Symbol	Parameter Description	Test Conditions	Min.	Max.	Unit	
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> = 4.5 V	I <sub>OH</sub> = -15 mA	2.4	V	
		V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -24 mA	2.0		
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> = 4.5 V	I <sub>OL</sub> = 48 mA		0.5	V
		V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>				
V <sub>IH</sub>	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs		2.0		V
V <sub>IL</sub>	Input LOW Level	Guaranteed input logical LOW voltage for all inputs			0.8	V
V <sub>I</sub>	Input Clamp Voltage	V <sub>CC</sub> = 4.5 V, I <sub>IN</sub> = -18 mA			-1.2	V
I <sub>IL</sub>	Input LOW Current	V <sub>CC</sub> = 5.5 V, V <sub>IN</sub> = 0.4 V	Data, $\overline{\text{CLR}}$		-1.0	mA
			$\overline{\text{OE}}$ , $\overline{\text{EN}}$ , CP		-2.0	
I <sub>IH</sub>	Input HIGH Current	V <sub>CC</sub> = 5.5 V, V <sub>IN</sub> = 2.7 V			50	μA
I <sub>I</sub>	Input HIGH Current	V <sub>CC</sub> = 5.5 V, V <sub>IN</sub> = 5.5 V			1.0	mA
I <sub>OZ</sub>	Output Off-State (Hi-Z) Output Current	V <sub>CC</sub> = 5.5 V	V <sub>O</sub> = 0.4 V		-50	μA
			V <sub>O</sub> = 2.4 V		50	
I <sub>SC</sub>	Output Short Circuit Current (Note 1)	V <sub>CC</sub> = 5.5 V		-75	-250	mA
I <sub>CC</sub>	Supply Current (Note 2)	V <sub>CC</sub> = 5.5 V Outputs Open $\overline{\text{EN}}$ = LOW	Over Temperature Range		140	mA
			+70°C		130	mA

### Notes:

- Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second.
- Clock input, CP, is HIGH after clocking in data to produce outputs = LOW.

**SWITCHING CHARACTERISTICS** ( $T_A = 25^\circ\text{C}$ ,  $V_{CC} = 5.0\text{ V}$ )

Parameter Symbol	Parameter Description	Test Conditions (Note 1)	Min.	Typ.	Max.	Unit	
$t_{PLH}$	Propagation Delay Clock to $Y_i$ ( $\overline{OE} = \text{LOW}$ )	$C_L = 50\text{ pF}$	3.5		8.5	ns	
$t_{PHL}$			3.5		10.5	ns	
$t_{PLH}$		$C_L = 300\text{ pF}$			14	ns	
$t_{PHL}$					18	ns	
$t_s$	Data to CP Setup Time	$C_L = 50\text{ pF}$	2.0	0		ns	
$t_H$	Data to CP Hold Time		2.0	0.5		ns	
$t_s$	Enable ( $\overline{EN} \downarrow$ ) to CP Setup Time		3.0	1.5		ns	
$t_s$	Enable ( $\overline{EN} \uparrow$ ) to CP Setup Time		3.0	1.5		ns	
$t_H$	Enable ( $\overline{EN}$ ) Hold Time		0	-1.5		ns	
$t_{PHL}$	Propagation Delay, Clear to $Y_i$				12.9	15.0	ns
$t_s$	Clear Recovery ( $\overline{CLR} \uparrow$ ) Time			5.0	1.1		ns
$t_{PWH}$	Clock Pulse Width		HIGH	5.0	3.5		ns
$t_{PWL}$		LOW	5.0	3.0		ns	
$t_{PWL}$	Clear ( $\overline{CLR} = \text{LOW}$ ) Pulse Width		5.0	4.0		ns	
$t_{ZH}$	Output Enable Time $\overline{OE} \downarrow$ to $Y_i$	$C_L = 300\text{ pF}$			17	ns	
$t_{ZL}$					21	ns	
$t_{ZH}$		$C_L = 50\text{ pF}$			11.5	12	ns
$t_{ZL}$					11.0	12	ns
$t_{HZ}$	Output Disable Time $\overline{OE} \uparrow$ to $Y_i$	$C_L = 50\text{ pF}$			9	ns	
$t_{LZ}$					9	ns	
$t_{HZ}$		$C_L = 5\text{ pF}$			5.2	8	ns
$t_{LZ}$					5.5	8	ns

**Note:**

1. See test circuit and waveforms (Chapter 2).



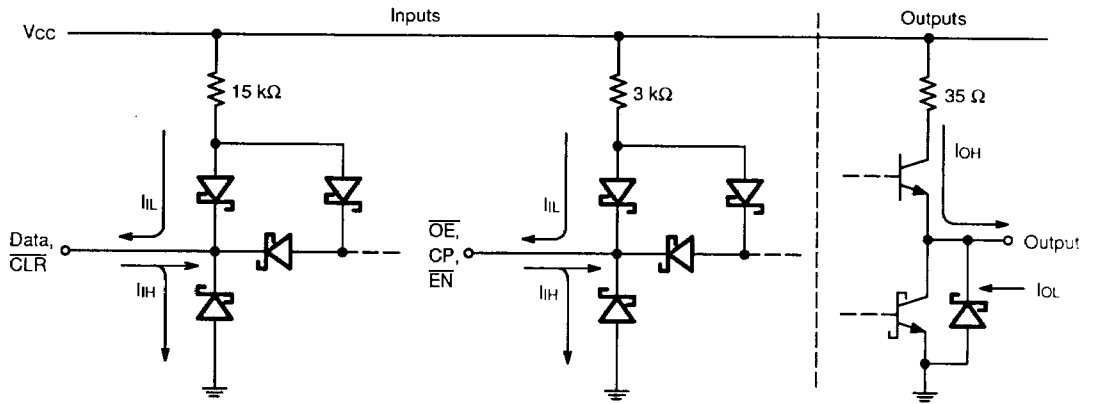
**SWITCHING CHARACTERISTICS** over operating ranges unless otherwise specified

Parameter Symbol	Parameter Description	Test Conditions (Note 1)	Min.	Max.	Unit	
t <sub>PLH</sub>	Propagation Delay Clock to Y <sub>i</sub> ( $\overline{OE}$ = LOW)	C <sub>L</sub> = 50 pF	3.5	10	ns	
t <sub>PHL</sub>			3.5	12	ns	
t <sub>PLH</sub>		C <sub>L</sub> = 300 pF		16	ns	
t <sub>PHL</sub>				20	ns	
t <sub>s</sub>	Data to CP Setup Time	C <sub>L</sub> = 50 pF	4		ns	
t <sub>h</sub>	Data to CP Hold Time		2		ns	
t <sub>s</sub>	Enable ( $\overline{EN}$ $\downarrow$ ) to CP Setup Time		4		ns	
t <sub>s</sub>	Enable ( $\overline{EN}$ $\uparrow$ ) to CP Setup Time		4		ns	
t <sub>h</sub>	Enable ( $\overline{EN}$ ) Hold Time		2		ns	
t <sub>PHL</sub>	Propagation Delay, Clear to Y <sub>i</sub>			20	ns	
t <sub>s</sub>	Clear Recovery ( $\overline{CLR}$ $\uparrow$ ) Time		7		ns	
t <sub>PWH</sub>	Clock Pulse Width		HIGH	7		ns
t <sub>PWL</sub>			LOW	7		ns
t <sub>PWL</sub>	Clear ( $\overline{CLR}$ = LOW) Pulse Width		7		ns	
t <sub>zH</sub>	Output Enable Time $\overline{OE}$ $\downarrow$ to Y <sub>i</sub>		C <sub>L</sub> = 300 pF		20	ns
t <sub>zL</sub>					23	ns
t <sub>zH</sub>		C <sub>L</sub> = 50 pF		14	ns	
t <sub>zL</sub>				14	ns	
t <sub>Hz</sub>	Output Disable Time $\overline{OE}$ $\uparrow$ to Y <sub>i</sub>	C <sub>L</sub> = 50 pF		16	ns	
t <sub>Lz</sub>				12	ns	
t <sub>Hz</sub>		C <sub>L</sub> = 5 pF		9	ns	
t <sub>Lz</sub>				9	ns	

**Note:**

1. See test circuit and waveforms (Chapter 2).

**INPUT/OUTPUT CURRENT INTERFACE CONDITIONS**

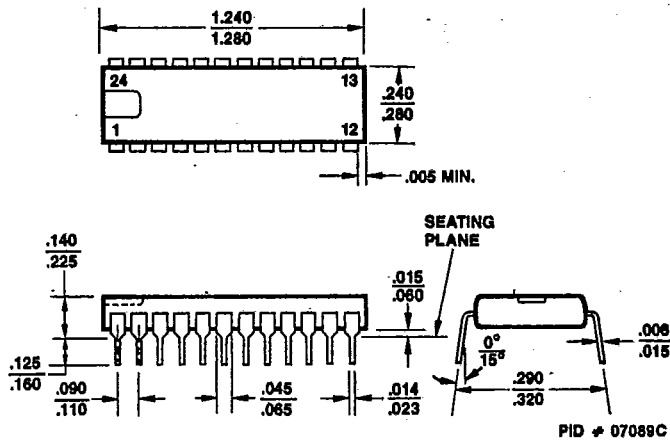


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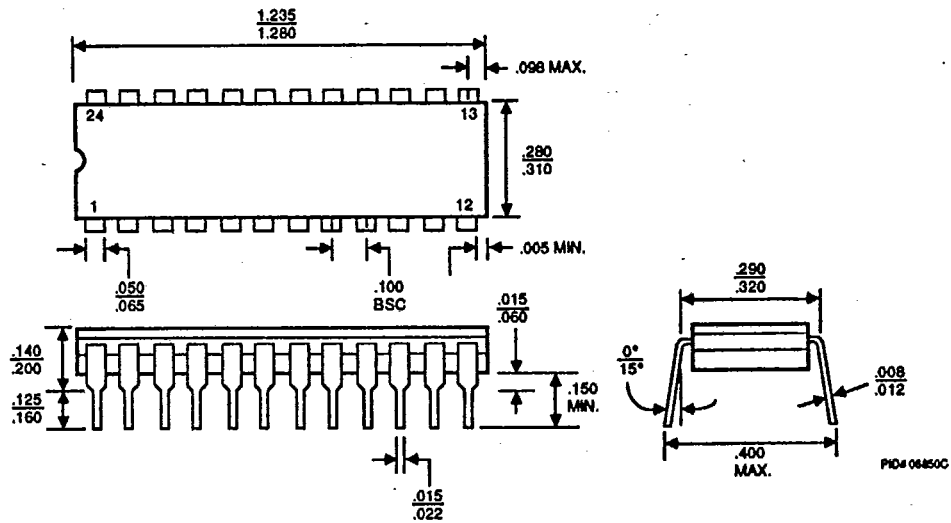
PACKAGE OUTLINES\*

T-90-20

PD3024



CD3024

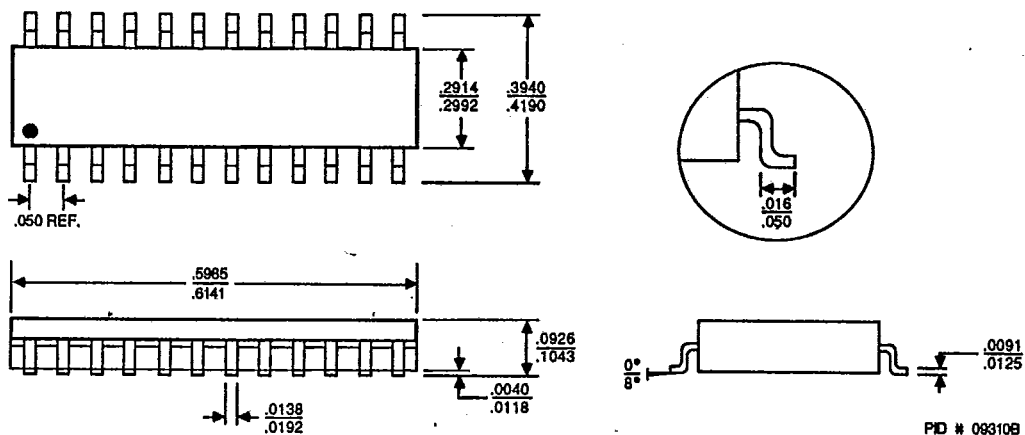


\*For reference only.

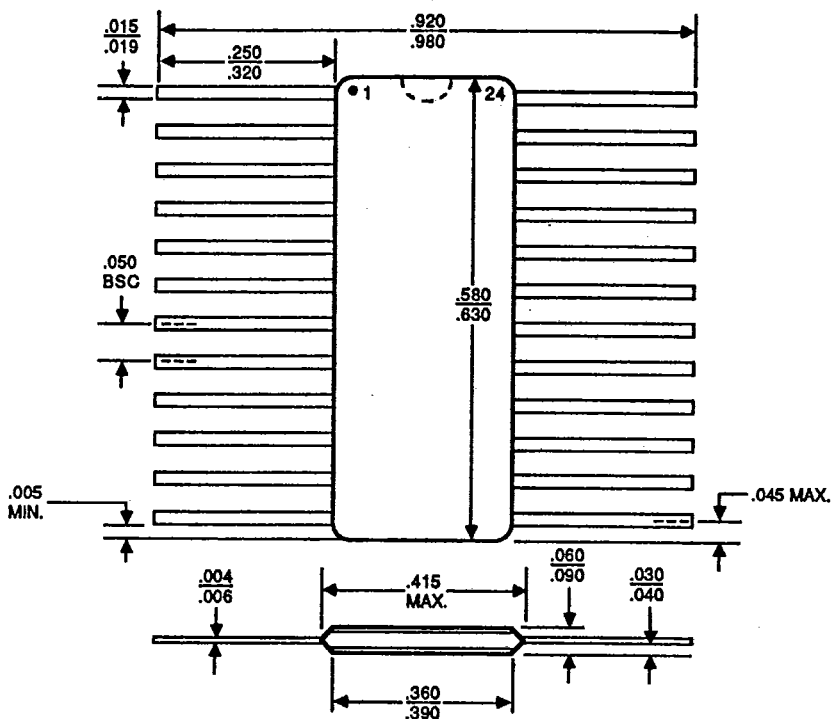
PACKAGE OUTLINES (Cont'd.)

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SO 024



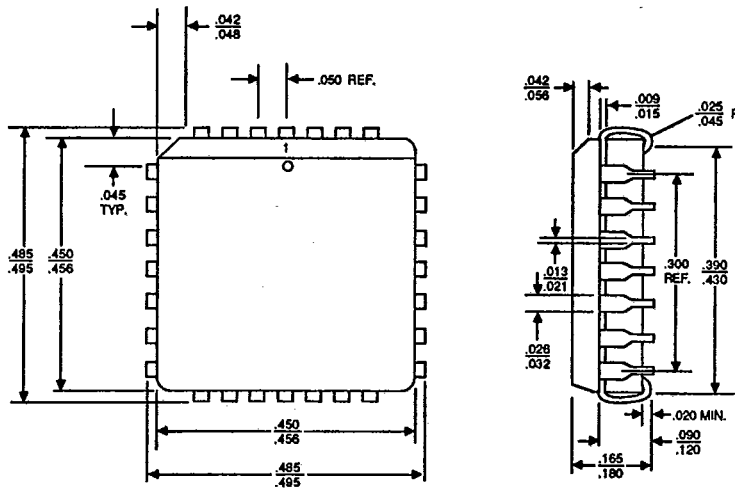
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PACKAGE OUTLINES (Cont'd.)

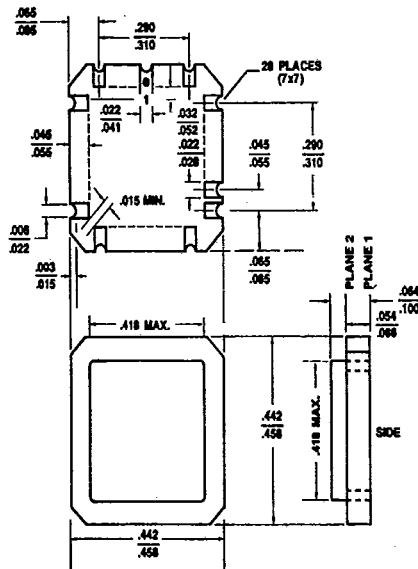
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PL 028



PID # 06751E

CL 028



PID # 06595D

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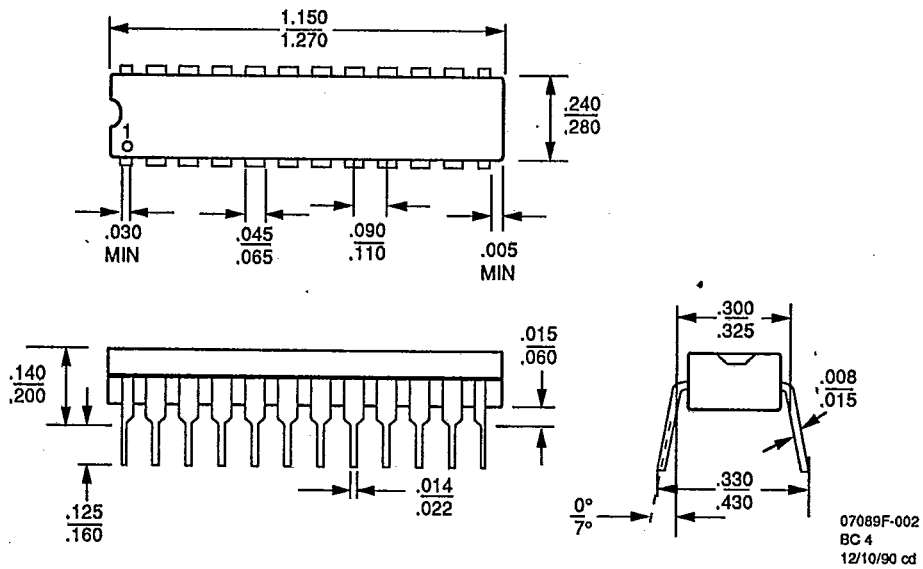


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**PD3024**  
**24-Pin 300-mil Plastic SKINNYDIP**

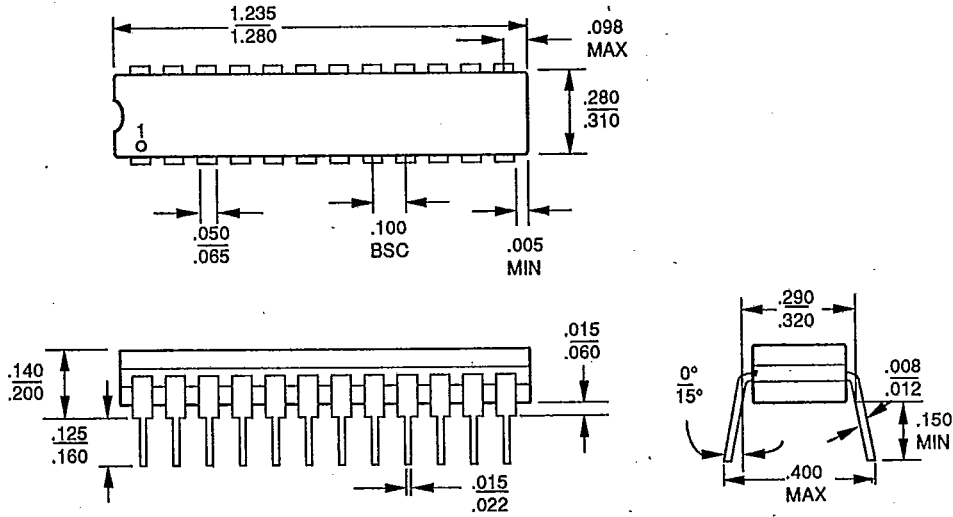
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**Note:**  
For reference only. All dimensions measured in inches. BSC is an ANSI standard for Basic Space Centering.

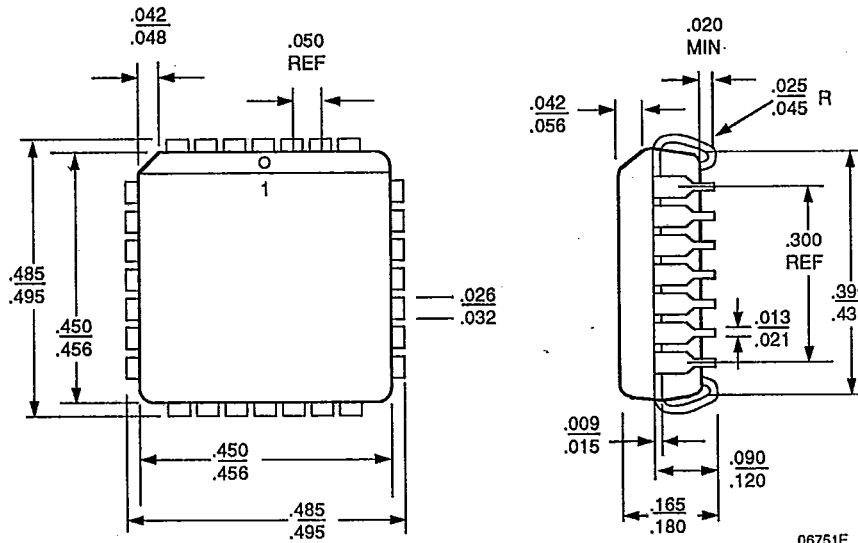
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**CD3024**  
**24-Pin 300-mil Ceramic SKINNYDIP**



06850C

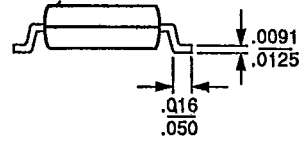
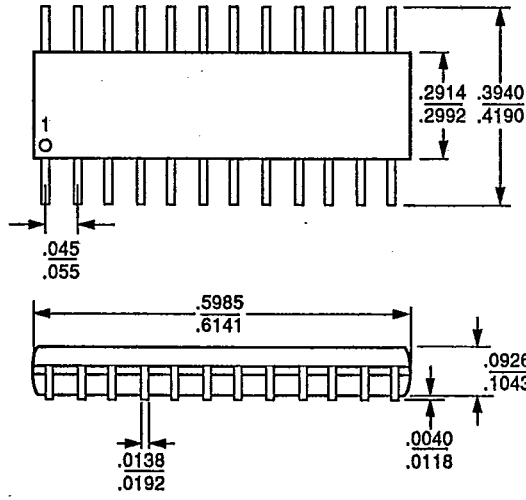
**PL 028**  
**28-Pin Plastic Leaded Chip Carrier**



06751E

**SO 024**  
**24-Pin Plastic Small Outline Package**

T-90-20



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